



FQD10N20C / FQU10N20C

200V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

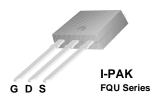
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, DC-AC converters for uninterrupted power supplies and motor controls.

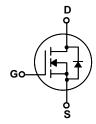
Features

- 7.8A, 200V, $R_{DS(on)} = 0.36\Omega @V_{GS} = 10 V$
- Low gate charge (typical 20 nC)
- Low Crss (typical 40.5 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQD10N20C / FQU10N20C	Units
V _{DSS}	Drain-Source Voltage		200	V
I _D	Drain Current - Continuous (T _C = 25°C)		7.8	Α
	- Continuous (T _C = 100°C)		5.0	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	31.2	Α
V_{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	210	mJ
I _{AR}	Avalanche Current	(Note 1)	7.8	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		50	W
	- Derate above 25°C		0.4	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W
	in the minimum pad size recommended (PCB Mount)		110	

Symbol	Parameter	Test Conditions	i	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	to 25°C	-	0.28		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 200 V, V _{GS} = 0 V		-		10	μΑ
		V _{DS} = 160 V, T _C = 125°C		-	-	100	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V		-		100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-	-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3.9 A		-	0.29	0.36	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 3.9 A	(Note 4)		5.6		S
C _{iss}	Input Capacitance Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz			395 97	510 125	pF pF
C _{rss}	Reverse Transfer Capacitance				40.5	53	pF
Switchi	ing Characteristics						
t _{d(on)}	Turn-On Delay Time	V_{DD} = 100 V, I_{D} = 9.5 A, R_{G} = 25 Ω (Note 4, 5)		1	11	30	ns
t _r	Turn-On Rise Time			-	92	190	ns
t _{d(off)}	Turn-Off Delay Time			1	70	150	ns
t _f	Turn-Off Fall Time			1	72	160	ns
Qg	Total Gate Charge	V_{DS} = 160 V, I_{D} = 9.5 A, V_{GS} = 10 V (Note 4, 5)		-	20	26	nC
Q _{gs}	Gate-Source Charge			1	3.1		nC
Q _{gd}	Gate-Drain Charge				10.5		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings	s				
Is	Maximum Continuous Drain-Source Diode Forward Current					7.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Orain-Source Diode Forward Current		1		31.2	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 7.8 \text{ A}$		1	-	1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 9.5 \text{ A},$		-	158		ns
Q _{rr}	Reverse Recovery Charge	dl _F / dt = 100 A/μs	(Note 4)	-	0.97		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 5.2mH, I_{AS} = 7.8A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 9.5A, di/dt \leq 300A/ μ s, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300 μ s, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

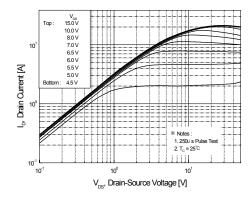


Figure 1. On-Region Characteristics

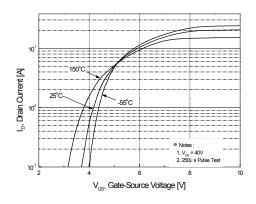


Figure 2. Transfer Characteristics

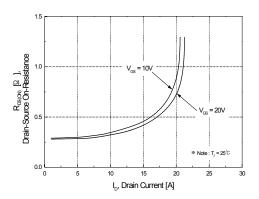


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

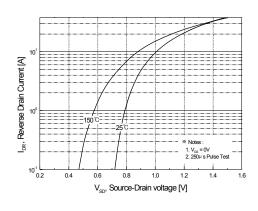


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

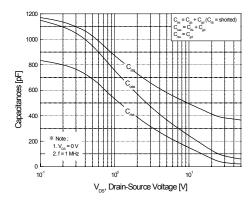


Figure 5. Capacitance Characteristics

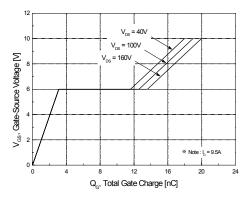


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

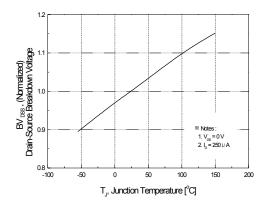
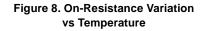
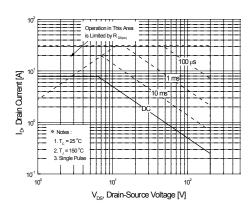


Figure 7. Breakdown Voltage Variation vs Temperature





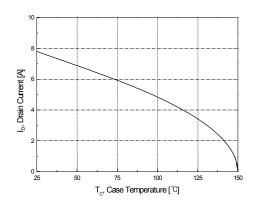


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

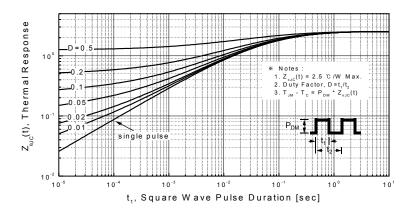
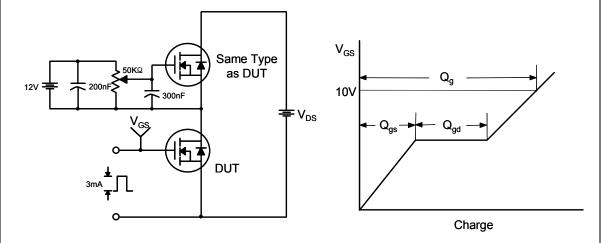


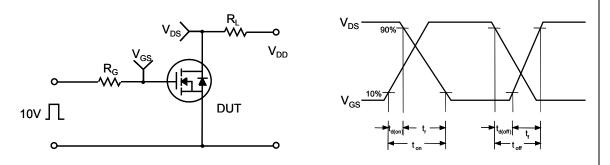
Figure 11. Transient Thermal Response Curve

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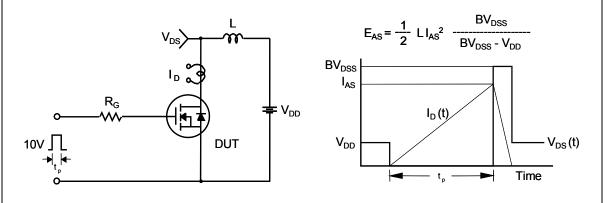
Gate Charge Test Circuit & Waveform



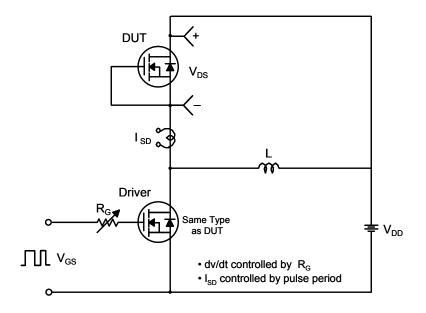
Resistive Switching Test Circuit & Waveforms

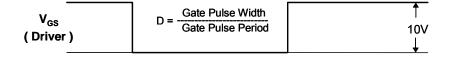


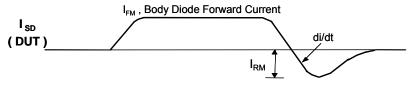
Unclamped Inductive Switching Test Circuit & Waveforms



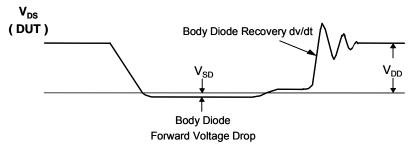
Peak Diode Recovery dv/dt Test Circuit & Waveforms





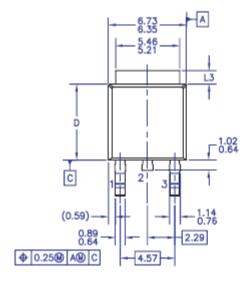


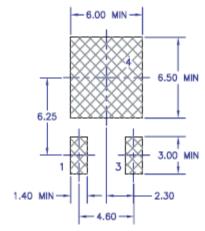
Body Diode Reverse Current



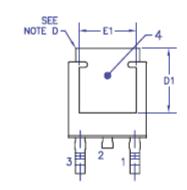
Package Dimensions

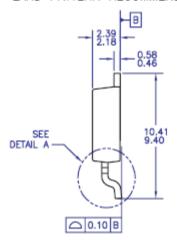
D - PAK

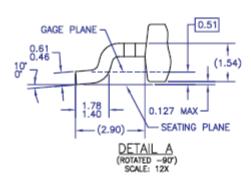




LAND PATTERN RECOMMENDATION







Dimensions in Millimeters

Package Dimensions I - PAK Scale 1:1 on letter size paper Dimensions shown below are in: millimeters Part Weight per unit (gram): 0.44 Α 6.80 6.35 2.50 2.10 5.54 5.14 0.60 0.40 - 1.52 0.70 2.28 - 1.60 6.30 5.90 C 2 9.65 8.90 _ 1.14 0.90 (0.60) — 2.29 0.88 0.64 ⊕ 0.25 M AM C 3 PLCS

Dimensions in Millimeters





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